

<b>Notice of References Cited</b>	Application/Control No. 10/565,833	Applicant(s)/Patent Under Reexamination YAMANAKA ET AL.	
	Examiner HIEN NGUYEN	Art Unit 3768	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,676,142	10-1997	Miwa et al.	600/310
	B	US-			
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	F	US-			
	G	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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